

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/617,826	CHEN ET AL.
Examiner	Art Unit	
Leon J. Harper	2166	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
707	10	11/17/2006	LJH
707	104.1	11/17/2006	LJH